EMC TEST REPORT

For

Shenzhen Huiju Camera Technology Co., Ltd.

Camera

Test Model: HJX35_V21_H-V2.0

Additional Models : HJX35_P68_V20-H-V1.0, HJY8A_S11-H-V2.0, HJY85_H2_H-V1.0

Prepared for	:	Shenzhen Huiju Camera Technology Co., Ltd.
Address	:	Room 404, Jiaanda Building, No.110, Huafan Road, Dalang Street , Longhua District, Shenzhen City, Guangdong, China
Prepared by	:	Shenzhen Southern LCS Compliance Testing Laboratory Ltd.
Address	:	101-201, No.39 Building, Xialang Industrial Zone, Heshuikou Community, Matian Street, Guangming District, Shenzhen, China
Tel	:	(+86)755-29871520
Fax	:	(+86)755-29871521
Web	:	www.LCS-cert.com
Mail	:	webmaster@LCS-cert.com
Date of receipt of test sample	:	June 28, 2021
Number of tested samples	:	1
Serial number	:	Prototype
Date of Test	:	June 28, 2021 ~ June 30, 2021
Date of Report	:	June 30, 2021

CE

EMC TEST REPORT

EN 55032:2015/A11:2020
Information technology equipment-Radio disturbance characteristics – Limits of measurement
EN 55035:2017/A11:2020
Electromagnetic compatibility of multimedia equipment – Immunity requirements

Report Reference No.	:	**LCS210628010BE**
Date of Issue.....	:	June 30, 2021
Testing Laboratory Name.....	:	**Shenzhen Southern LCS Compliance Testing Laboratory**
Address.....	:	101-201, No.39 Building, Xialang Industrial Zone, Heshuikou Community, Matian Street, Guangming District, Shenzhen, China.
Testing Location/ Procedure	:	Full application of Harmonised standards ■ Partial application of Harmonised standards □ Other standard testing method □
Applicant's Name	:	**Shenzhen Huiju Camera Technology Co., Ltd.**
Address.....	:	Room 404, Jiaanda Building, No.110, Huafan Road, Dalang Street , Longhua District, Shenzhen City, Guangdong, China
Test Specification		
Standard.....	:	EN 55032:2015/A11:2020, EN IEC 61000-3-2: 2019 EN 61000-3-3:2013+A1:2019, EN 55035:2017/A11:2020
Test Report Form No.....	:	LCSEMC-1.0
TRF Originator.....	:	Shenzhen Southern LCS Compliance Testing Laboratory Ltd.
Master TRF.....	:	Dated 2016-08

Test Item Description.....	:	**Camera**
Trade Mark.....	:	N/A
Test Model.....	:	HJX35_V21_H-V2.0
Ratings	:	DC 5V
Result	:	**PASS**

Compiled by:	**Supervised by:**	**Approved by:**
Aimee Yang	Dmgu	Cherry Chen
Aimee Yang / File administrators	Dm Gu/ Technique principal	Cherry Chen/ Manager

EMC -- TEST REPORT

Test Report No. : LCS210628010BE	June 30, 2021 Date of issue

Test Model.....	:	HJX35_V21_H-V2.0
EUT.....	:	Camera
Applicant.....	**:**	**Shenzhen Huiju Camera Technology Co., Ltd.**
Address.....	:	Room 404, Jiaanda Building, No.110, Huafan Road, Dalang Street , Longhua District, Shenzhen City, Guangdong, China
Telephone.....	:	
Fax.....	:	
Manufacturer.....	**:**	**Shenzhen Huiju Camera Technology Co., Ltd.**
Address.....	:	Room 404, Jiaanda Building, No.110, Huafan Road, Dalang Street , Longhua District, Shenzhen City, Guangdong, China
Telephone.....	:	
Fax.....	:	
Factory.....	**:**	**Shenzhen Huiju Camera Technology Co., Ltd.**
Address.....	:	Room 404, Jiaanda Building, No.110, Huafan Road, Dalang Street , Longhua District, Shenzhen City, Guangdong, China
Telephone.....	:	
Fax.....	:	

Test Result	**PASS**

The test report merely corresponds to the test sample.
It is not permitted to copy extracts of these test result without the written permission of the test laboratory.

Revision History

Revision	Issue Date	Revisions	Revised By
000	June 30, 2021	Initial Issue	Cherry Chen

TABLE OF CONTENTS

Page

1. SUMMARY OF STANDARDS AND RESULTS

1.1. Description of Standards and Results

The EUT have been tested according to the applicable standards as referenced below.

Emission (EN 55032:2015/A11:2020)			
Description of Test Item	**Standard**	**Limits**	**Results**
Conducted disturbance at mains terminals	EN 55032:2015/A11:2020	Class B	N/A
Conducted disturbance at telecommunication port	EN 55032:2015/A11:2020	Class B	N/A
Radiated disturbance	EN 55032:2015/A11:2020	Class B	PASS
Harmonic current emissions	EN IEC 61000-3-2: 2019	Class A	N/A
Voltage fluctuations & flicker	EN 61000-3-3:2013+A1:2019	---------	N/A
Immunity (EN 55035:2017/A11:2020)			
Description of Test Item	**Basic Standard**	**Performance Criteria**	**Results**
Electrostatic discharge (ESD)	EN 61000-4-2: 2009	B	PASS
Radio-frequency, Continuous radiated disturbance	EN 61000-4-3: 2006+A2: 2010	A	PASS
Electrical fast transient (EFT)	EN 61000-4-4: 2012	B	N/A
Surge (Input a.c. power ports)	EN 61000-4-5: 2014+A1: 2017	B	N/A
Surge (Telecommunication ports)		B	N/A
Radio-frequency, Continuous conducted disturbance	EN 61000-4-6: 2014	A	N/A
Power frequency magnetic field	EN 61000-4-8: 2010	A	PASS
Voltage dips, >95% reduction	EN 61000-4-11: 2004+A1: 2017	B	N/A
Voltage dips, 30% reduction		C	N/A
Voltage interruptions		C	N/A
***Note: N/A is an abbreviation for Not Applicable.			

2.1. Description of Performance Criteria

General Performance Criteria
Examples of functions defined by the manufacturer to be evaluated during testing include, but are not limited to, the following:
— essential operational modes and states;
— tests of all peripheral access (hard disks, floppy disks, printers, keyboard, mouse, etc.);
— quality of software execution;
— quality of data display and transmission;
— quality of speech transmission.

1.2.1. Performance criterion A
The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacture when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be deriver from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

1.2.2. Performance criterion B
After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacture, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.

During the test, degradation of performance is allowed. However, no change of operation state or stored data is allowed to persist after the test.

If the minimum performance level (or the permissible performance loss) is not specified by the manufacturer, then either of these may be deriver from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

1.2.3. Performance criterion C
Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacture's instructions.

Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be loss.

2. GENERAL INFORMATION

2.1. Description of Device (EUT)

EUT : Camera

Trade Mark : N/A

Test Model : HJX35_V21_H-V2.0

EUT Clock Frequency : ≤ 108MHz

2.2 Support equipment List

Configuration	Model	Rating	Manufacturer
Notebook computer	G50	/	Lenovo

2.3. Description of Test Facility

EMC Lab. : TUV RH Registration Number. is UA 50418075 0001.
UL Registration Number. is 100571-492.
NVLAP Registration Code is 600112-0.

Test Facilities : Shenzhen Southern LCS Compliance Testing Laboratory Ltd.
101-201, No.39 Building,Xialang Industrial Zone, Heshuikou Community, Matian Street, Guangming District, Shenzhen, China.

RF Field Strength Susceptibility : Shenzhen LCS Compliance Testing Laboratory Ltd.
101, 201 Building A and 301 Building C, Juji Industrial Park, Yabianxueziwei, Shajing Street, Baoan District, Shenzhen, Guangdong, China

2.4. Statement of The Measurement Uncertainty

The data and results referenced in this document are true and accurate. The reader is cautioned that there may be errors within the calibration limits of the equipment and facilities. The measurement uncertainty was calculated for all measurements listed in this test report acc. To CISPR 16 – 4 “Specification for radio disturbance and immunity measuring apparatus and methods – Part 4: Uncertainty in EMC Measurements” and is documented in the LCS quality system acc. To DIN EN ISO/IEC 17025. Furthermore, component and process variability of devices similar to that tested may result in additional deviation. The manufacturer has the sole responsibility of continued compliance of the device.

2.5. Measurement Uncertainty

Test	Parameters	Expanded uncertainty (U_{lab})	Expanded uncertainty (U_{cispr})
Conducted Emission	Level accuracy (9kHz to 150kHz) (150kHz to 30MHz)	± 2.63 dB ± 2.35 dB	± 3.8 dB ± 3.4 dB
Power disturbance	Level accuracy (30MHz to 300MHz)	± 2.90dB	± 4.5 dB
Electromagnetic Radiated Emission (3-loop)	Level accuracy (9kHz to 30MHz)	± 3.60 dB	± 3.3 dB
Radiated Emission	Level accuracy (9kHz to 30MHz)	± 3.68 dB	N/A
Radiated Emission	Level accuracy (30MHz to 1000MHz)	± 3.48 dB	± 5.3 dB
Radiated Emission	Level accuracy (above 1000MHz)	± 3.90 dB	± 5.2 dB
Harmonic	Voltage	± 0.510%	N/A
Voltage Fluctuations & Flicker	Voltage	± 0.510%	N/A
1) Where relevant, the following measurement uncertainty levels have been estimated for tests performed on the apparatus. 2) The reported expanded uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor of k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.			

3. MEASURING DEVICES AND TEST EQUIPMENT

Radiated Disturbance

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Due Date.
1	3m Semi Anechoic Chamber	SIDT FRANKONIA	SAC-3M	03CH03-HY	2024-06-15
2	EMI Test Receiver	R&S	ESCI3	101010	2022-06-08
3	Spectrum analyzer	Agilent	N9020A	MY49100699	2022-06-08
4	Log per Antenna	SCHWARZBECK	VULB9163	5094	2022-06-23
5	Horn antenna	ETS-LINDGREN	3115	00034771	2022-06-23
6	EMI Test Software	EZ	EZ_EMC	N/A	/
7	Positioning Controller	MF	BK8807-4A-2T	2016-0808-008	/

Electrostatic Discharge Immunity Test (ESD)

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Due Date.
1	ESD Simulator	TESEQ	NSG 437	1615	2022-03-24

Power Frequency Magnetic Field Immunity Test

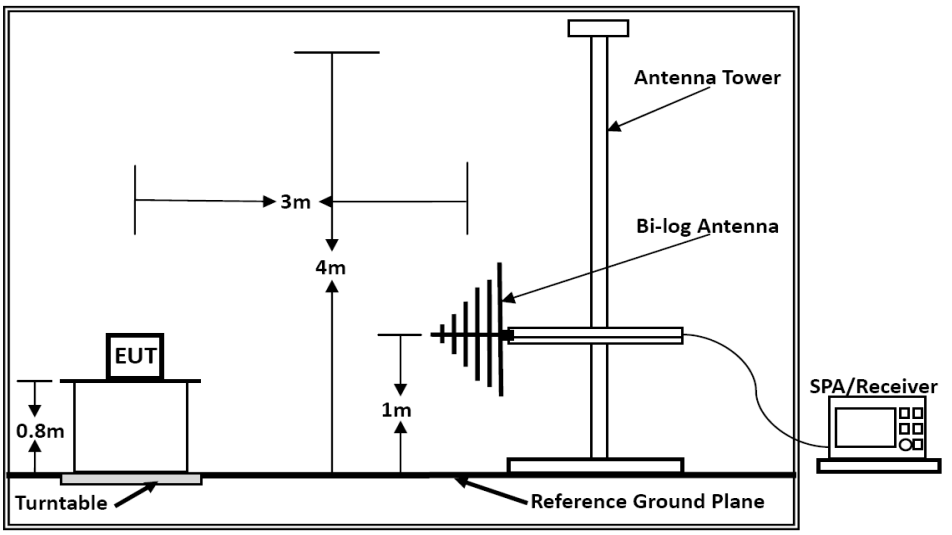
Item	Test Equipment	Manufacturer	Model No.	Serial No.	Due Date.
1	Power frequency mag-field generator System	HTEC	HPFMF100	100-2400	2022-06-08

Radiated, Radio-Frequency, Electromagnetic Field Immunity Test

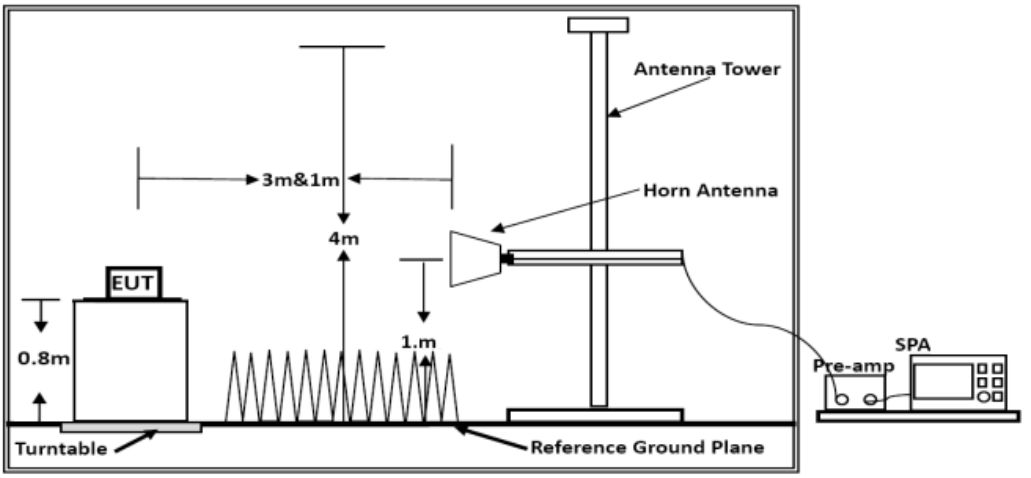
Item	Test Equipment	Manufacturer	Model No.	Serial No.	Due Date.
1	RS Test Software	Tonscend	/	/	N/A
2	ESG Vector Signal Generator	Agilent	E4438C	MY42081396	2021-11-14
3	3m Semi Anechoic Chamber	SIDT FRANKONIA	SAC-3M	03CH03-HY	2023-06-11
4	RF POWER AMPLIFIER	OPHIR	5225R	1052	2021-11-21
5	RF POWER AMPLIFIER	OPHIR	5273F	1019	2021-11-21
6	Stacked Broadband Log Periodic Antenna	SCHWARZBECK	STLP 9128	9128ES-145	2021-11-21
7	Stacked Mikrowellen Log.-Per Antenna	SCHWARZBECK	STLP 9149	9149-484	2021-11-21
8	RS Test Software	Tonscend	/	/	2022-03-24

4. RADIATED EMISSION MEASUREMENT

4.1. Block Diagram of Test Setup



Below 1GHz



Above 1GHz

4.2. Test Standard

EN 55032:2015/A11:2020

All emanations from a class B device or system, including any network of conductors and apparatus connected thereto, shall not exceed the level of field strengths specified below:

Limits for Radiated Emission Below 1GHz(Class B)		
Frequency (MHz)	Distance (Meters)	Field Strengths Limit (dBμV/m)
30 ~ 230	3	40
230 ~ 1000	3	47
Note: (1) The smaller limit shall apply at the combination point between two frequency bands. (2) Distance refers to the distance in meters between the measuring instrument antenna and the closed point of any part of the EUT.		

Limits for Radiated Emission Above 1GHz(Class B)			
Frequency (MHz)	Distance (Meters)	Peak Limit (dBμV/m)	Average Limit (dBμV/m)
1000 ~ 3000	3	70	50
3000 ~ 6000	3	74	54
***Note: The lower limit applies at the transition frequency.			

All emanations from a class A device or system, including any network of conductors and apparatus connected thereto, shall not exceed the level of field strengths specified below:

Limits for Radiated Emission Below 1GHz(Class A)		
Frequency (MHz)	Distance (Meters)	Field Strengths Limit (dBμV/m)
30 ~ 230	3	50
230 ~ 1000	3	57
Note: (1) The smaller limit shall apply at the combination point between two frequency bands. (2) Distance refers to the distance in meters between the measuring instrument antenna and the closed point of any part of the EUT.		

Limits for Radiated Emission Above 1GHz(Class A)			
Frequency (MHz)	Distance (Meters)	Peak Limit (dBμV/m)	Average Limit (dBμV/m)
1000 ~ 3000	3	76	56
3000 ~ 6000	3	80	60
***Note: The lower limit applies at the transition frequency.			

4.3. EUT Configuration on Test

The EN 55032 regulations test method must be used to find the maximum emission during radiated emission measurement.

4.4. Operating Condition of EUT

1) Turn on the power.
2) Let the EUT work in the test mode (1) and measure it.

4.5. Test Procedure

The EUT is placed on a turntable, which is 0.8 meter high above the ground. The turntable can rotate 360 degrees to determine the position of the maximum emission level. The EUT is set 3 meters away from the receiving antenna, which is mounted on a antenna tower. The antenna can be moved up and down from 1 to 4 meters to find out the maximum emission level. By-log antenna is used as a receiving antenna. Both horizontal and vertical polarization of the antenna is set on test.
The bandwidth of the EMI test receiver is set at RBW/VBW=120kHz/1000kHz.
The frequency range from 30MHz to 1000MHz is checked.
The bandwidth of the Spectrum analyzer is set at RBW/VBW=1MHz/3MHz.
The frequency range from 1GHz to the frequency which about 5th carrier harmonic or 6GHz is checked.

4.6. Test Results

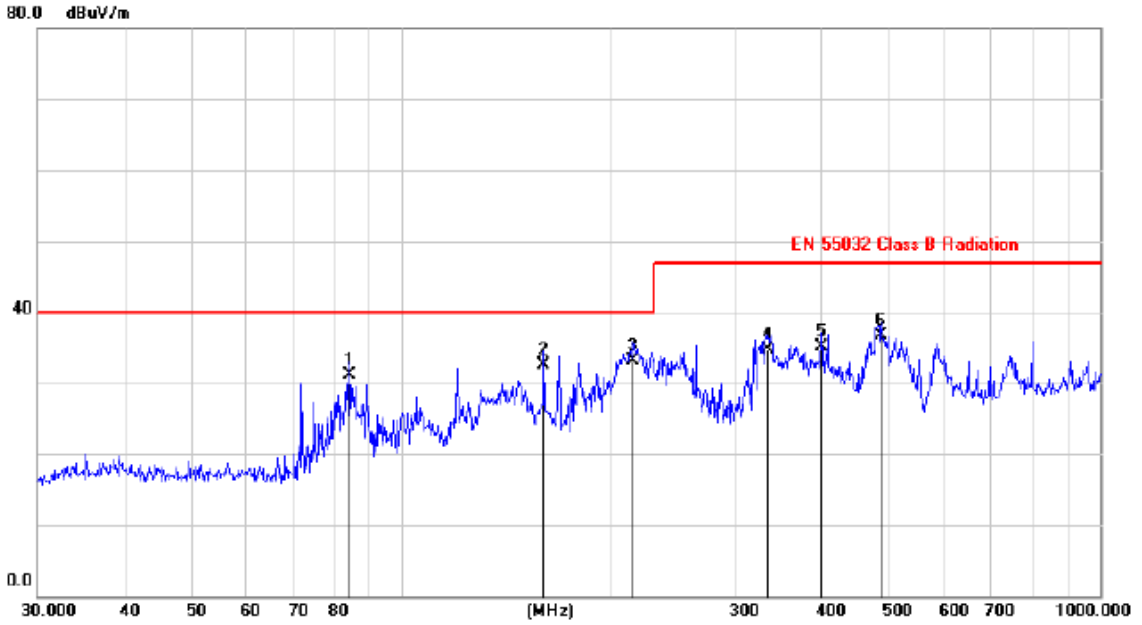
PASS.

The test result please refer to the next page.

Test Model	HJX35_V21_H-V2.0	**Test Mode**	Working
Environmental Conditions	22.9℃, 57% RH	**Detector Function**	Quasi-peak
Pol.	Vertical	**Distance**	3m
Test Engineer	Peng Dong	**Test Voltage**	DC 5V

No.	Mk.	Freq.	Reading Level	Correct Factor	Measure-ment	Limit	Margin		Antenna Height	Table Degree	
		MHz	dBuV	dB/m	dBuV/m	dBuV/m	dB	Detector	cm	degree	Comment
1		137.0593	15.06	13.36	28.42	40.00	-11.58	QP			
2	*	159.9947	19.96	13.13	33.09	40.00	-6.91	QP			
3		217.0681	20.06	9.56	29.62	40.00	-10.38	QP			
4		358.5568	13.31	14.49	27.80	47.00	-19.20	QP			
5		480.1065	15.98	17.02	33.00	47.00	-14.00	QP			
6		666.9719	11.36	20.87	32.23	47.00	-14.77	QP			

Test Model	HJX35_V21_H-V2.0	**Test Mode**	Working
Environmental Conditions	22.9℃, 57% RH	**Detector Function**	Quasi-peak
Pol.	Horizontal	**Distance**	3m
Test Engineer	Peng Dong	**Test Voltage**	DC 5V

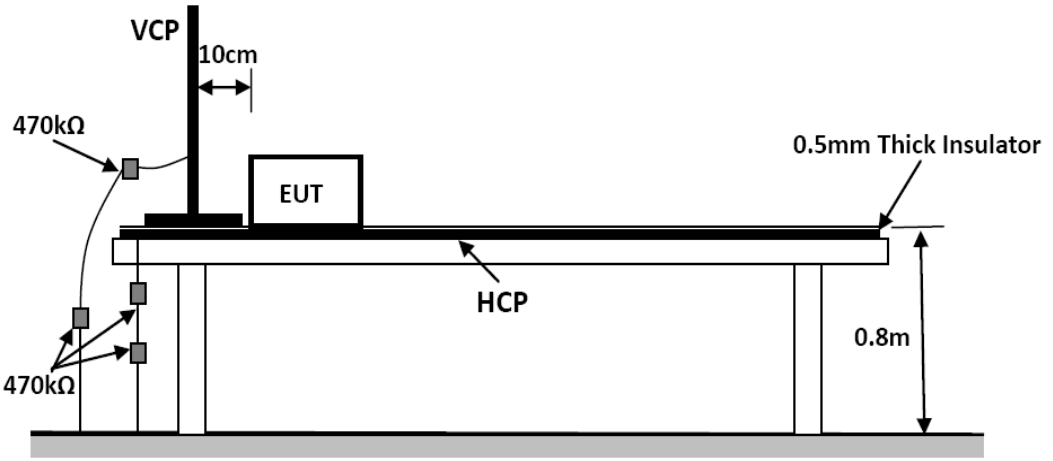


No.	Mk.	Freq.	Reading Level	Correct Factor	Measure-ment	Limit	Margin		Antenna Height	Table Degree	
		MHz	dBuV	dB/m	dBuV/m	dBuV/m	dB	Detector	cm	degree	Comment
1		84.2207	21.14	10.01	31.15	40.00	-8.85	QP			
2		159.9944	22.54	9.88	32.42	40.00	-7.58	QP			
3	*	214.9849	20.85	12.18	33.03	40.00	-6.97	QP			
4		333.6865	20.17	14.58	34.75	47.00	-12.25	QP			
5		400.0810	19.58	15.47	35.05	47.00	-11.95	QP			
6		485.8222	19.07	17.55	36.62	47.00	-10.38	QP			

Remark: Pre-San all mode, Thus record worse case mode result in this report

5. ELECTROSTATIC DISCHARGE IMMUNITY TEST

5.1. Block Diagram of Test Setup



5.2. Test Standard

EN 55035:2017/A11:2020 (EN 61000-4-2: 2009, Severity Level: 3 / Air Discharge: ±8KV, Level: 2 / Contact Discharge: ±4KV)

5.3. Severity Levels and Performance Criterion

5.3.1. Severity level

Level	Test Voltage Contact Discharge (KV)	Test Voltage Air Discharge (KV)
1	±2	±2
2	±4	±4
3	±6	±8
4	±8	±15
X	Special	Special

5.3.2. Performance Criterion：B

5.4. EUT Configuration on Test

The configuration of EUT is listed in Section 4.3.

5.5. Operating Condition of EUT

Same as conducted emission measurement, which is listed in Section 3. Except the test set up replaced by Section 5.1.

5.6. Test Procedure

6.6.1. Air Discharge

This test is done on a non-conductive surface. The round discharge tip of the discharge electrode shall be approached as fast as possible to touch the EUT. After each discharge, the discharge electrode shall be removed from the EUT. The generator is then re-triggered for a new single discharge and repeated 10 times for each pre-selected test point. This procedure shall be repeated until all the air discharge completed

6.6.2. Contact Discharge

All the procedure shall be same as Section 9.6.1. Except that the tip of the discharge electrode shall touch the EUT before the discharge switch is operated.

6.6.3. Indirect Discharge For Horizontal Coupling Plane

At least 10 single discharges (in the most sensitive polarity) shall be applied at the front edge of each HCP opposite the center point of each unit (if applicable) of the EUT and 0.1m from the front of the EUT. The long axis of the discharge electrode shall be in the plane of the HCP and perpendicular to its front edge during the discharge.

6.6.4. Indirect Discharge For Vertical Coupling Plane

At least 10 single discharge (in the most sensitive polarity) shall be applied to the center of one vertical edge of the coupling plane. The coupling plane, of dimensions 0.5m X 0.5m, is placed parallel to, and positioned at a distance of 0.1m from the EUT. Discharges shall be applied to the coupling plane, with this plane in sufficient different positions that the four faces of the EUT are completely illuminated.

5.7. Test Results

PASS.

The test result please refer to the next page.

Electrostatic Discharge Test Results

Standard	☐ IEC 61000-4-2 ☑ EN 61000-4-2		
Applicant	Shenzhen Huiju Camera Technology Co., Ltd.		
EUT	Camera	**Temperature**	23.6℃
M/N	HJX35_V21_H-V2.0	**Humidity**	53%
Criterion	B	**Pressure**	1021mbar
Test Mode	Working	**Test Engineer**	Peng Dong
Test Voltage	DC 5V		

Air Discharge

Test Points	Test Levels			Results		
	± 2kV	± 4kV	± 8kV	Passed	Fail	Performance Criterion
Front	☒	☒	☒	☒	☐	☐A ☒B
Back	☒	☒	☒	☒	☐	☐A ☒B
Left	☒	☒	☒	☒	☐	☐A ☒B
Right	☒	☒	☒	☒	☐	☐A ☒B
Top	☒	☒	☒	☒	☐	☐A ☒B
Bottom	☒	☒	☒	☒	☐	☐A ☒B

Contact Discharge

Test Points	Test Levels		Results		
	± 2 kV	±4 kV	Passed	Fail	Performance Criterion
Front	☒	☒	☒	☐	☐A ☒B
Back	☒	☒	☒	☐	☐A ☒B
Left	☒	☒	☒	☐	☐A ☒B
Right	☒	☒	☒	☐	☐A ☒B
Top	☒	☒	☒	☐	☐A ☒B
Bottom	☒	☒	☒	☐	☐A ☒B

Discharge To Horizontal Coupling Plane

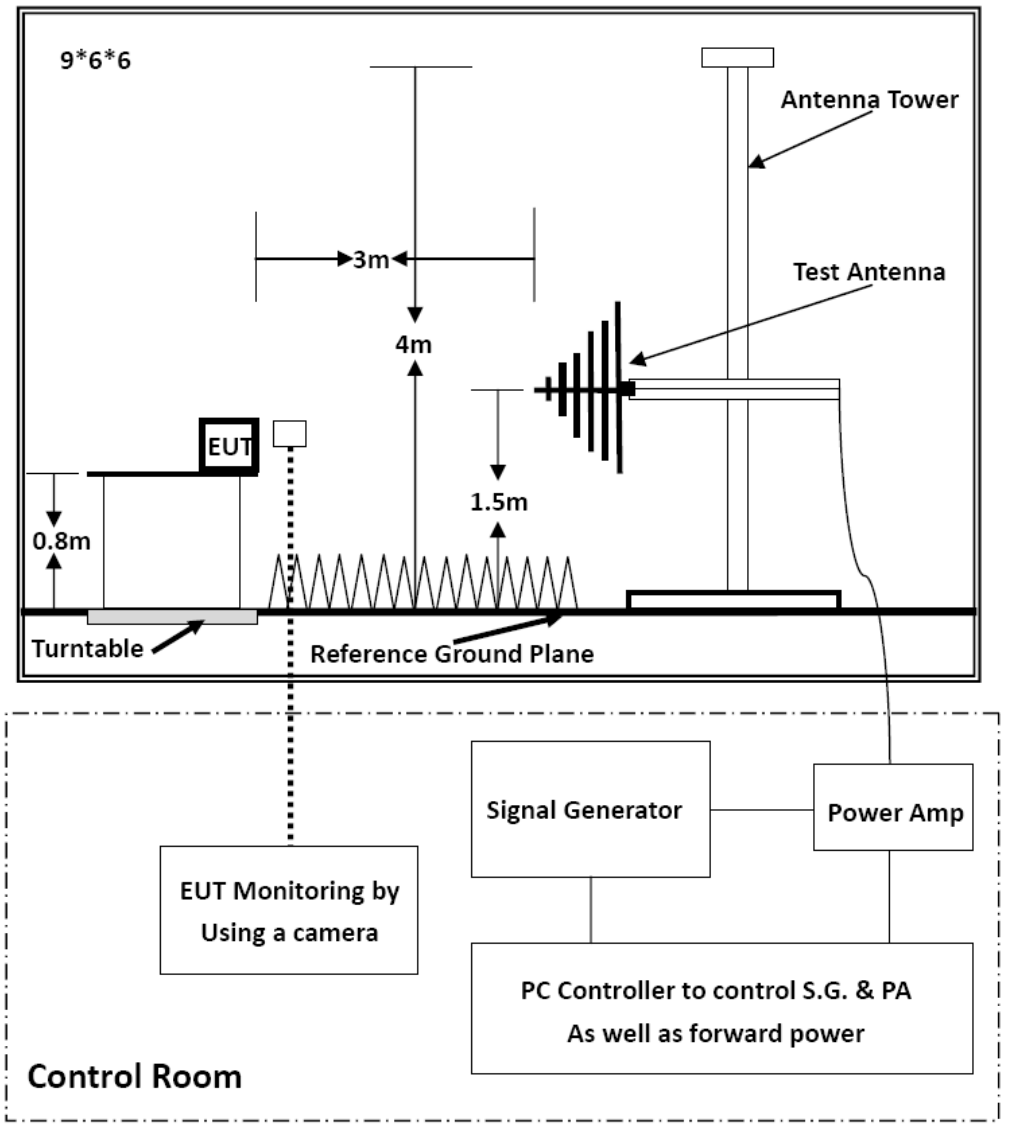
Side of EUT	Test Levels		Results		
	± 2 kV	± 4 kV	Passed	Fail	Performance Criterion
Front	☒	☒	☒	☐	☐A ☒B
Back	☒	☒	☒	☐	☐A ☒B
Left	☒	☒	☒	☐	☐A ☒B
Right	☒	☒	☒	☐	☐A ☒B

Discharge To Vertical Coupling Plane

Side of EUT	Test Levels		Results		
	± 2 kV	± 4 kV	Passed	Fail	Performance Criterion
Front	☒	☒	☒	☐	☐A ☒B
Back	☒	☒	☒	☐	☐A ☒B
Left	☒	☒	☒	☐	☐A ☒B
Right	☒	☒	☒	☐	☐A ☒B

6. RF FIELD STRENGTH SUSCEPTIBILITY TEST

6.1. Block Diagram of Test Setup



6.2. Test Standard

EN 55035:2017/A11:2020 (Test Level: 3V/m)

6.3. Severity Levels and Performance Criterion

6.3.1. Severity level

Level	Field Strength (V/m)
1	1
2	3
3	10
X	1

6.3.2. Performance Criterion: A

6.4. EUT Configuration on Test

The configuration of EUT is listed in Section 4.3.

6.5. Operating Condition of EUT

Same as radiated emission measurement, which is listed in Section 4.1, except the test setup replaced as Section 6.1.

6.6. Test Procedure

The EUT are placed on a table, which is 0.8 meter high above the ground. The EUT is set 3 meters away from the transmitting antenna, which is mounted on an antenna tower. Both horizontal and vertical polarization of the antenna is set on test. Each of the four sides of the EUT must be faced this transmitting antenna and measured individually.
In order to judge the EUT performance, a CCD Recording is used to monitor its screen.
All the scanning conditions are as following:

Condition of Test	Remark
Fielded Strength	3 V/m (Severity Level 2)
Radiated Signal	Unmodulated
Test Frequency Range (swept test)	80-1000MHz
Test Frequency (spot test)	1800MHz, 2600MHz, 3500MHz, 5000MHz
Dwell time of radiated	0.0015 decade/s
Waiting Time	3 Sec.

6.7. Test Results

PASS.

The test result please refer to the next page.

RF Field Strength Susceptibility Test Results

Standard	☐ IEC 61000-4-3 ☑ EN 61000-4-3		
Applicant	Shenzhen Huiju Camera Technology Co., Ltd.		
EUT	Camera	**Temperature**	23.5℃
M/N	HJX35_V21_H-V2.0	**Humidity**	53%
Field Strength	3 V/m	**Criterion**	A
Test Mode	Working	**Test Engineer**	Daiwei Dai
Test Frequency	80MHz to 1000MHz (swept test) 1800MHz, 2600MHz, 3500MHz, 5000MHz (spot test)	**Test Voltage**	DC 5V
Modulation	☐None ☐ Pulse ☑AM 1KHz 80%		
Steps	1%		

	Horizontal	**Vertical**
Front	PASS	PASS
Right	PASS	PASS
Rear	PASS	PASS
Left	PASS	PASS

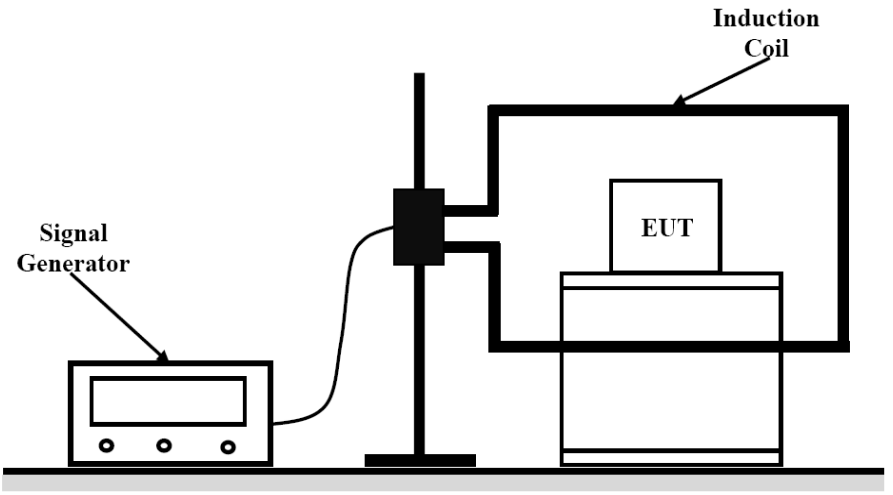
Test Equipment:

1. Signal Generator: 2031 (MARCONI)
2. Power Amplifier: 500A100 & 100W/1000M1 (A&R)
3. Power Antenna: 3108 (EMCO) & AT1080 (A&R)
4. Field Monitor: FM2000 (A&R)

Note:

7. MAGNETIC FIELD SUSCEPTIBILITY TEST

7.1. Block Diagram of Test Setup



7.2. Test Standard

EN 55035:2017/A11:2020 (EN 61000-4-8: 2010, Severity Level: Level 1, 1A/m)

7.3. Severity Levels and Performance Criterion

7.3.1. Severity level

Level	Field Strength (A/m)
1	1
2	3
3	10
4	30
5	100
X	Special

7.3.2. Performance Criterion: A

7.4. EUT Configuration on Test

The configuration of EUT is listed in Section 3.

7.5. Test Procedure

The EUT is placed in the middle of a induction coil (1*1m), under which is a 1*1*0.1m (high) table, this small table is also placed on a larger table, 0.8 m above the ground. Both horizontal and vertical polarization of the induction coil is set on test, so that each side of the EUT is affected by the magnetic field. Also can reach the same aim by change the position of the EUT.

7.6. Test Results

PASS.

The test result please refer to the next page.

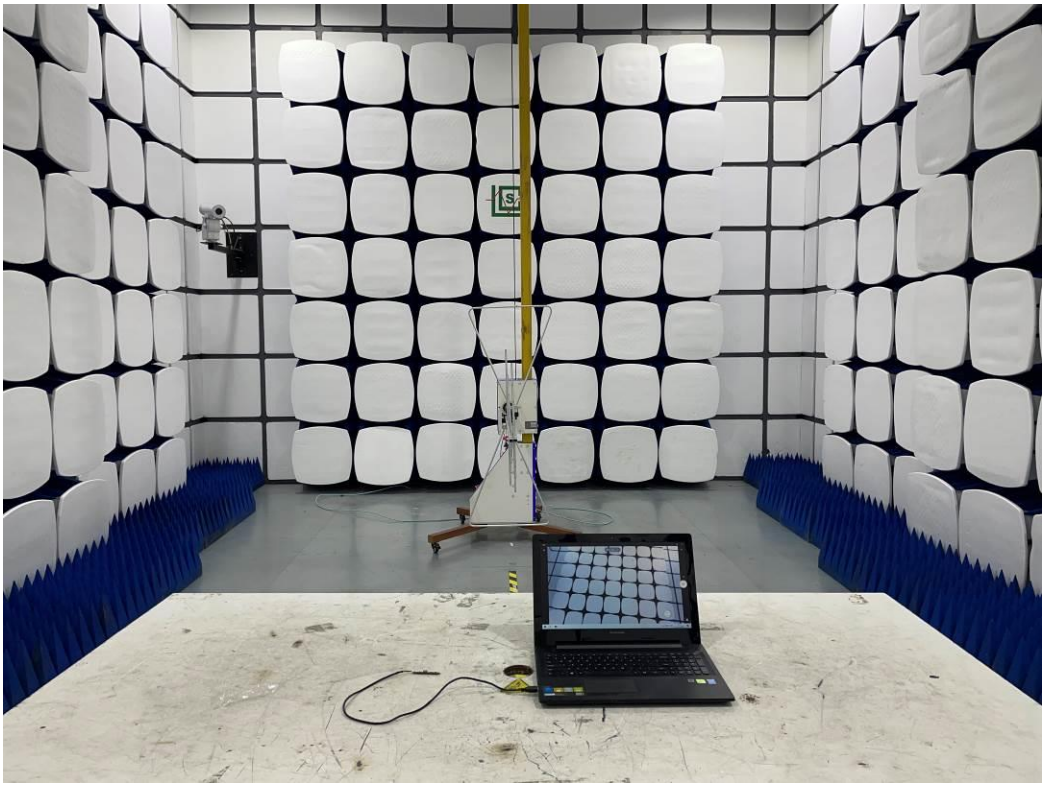
Magnetic Field Immunity Test Result

Standard	☐ IEC 61000-4-8	☑ EN 61000-4-8	
Applicant	Shenzhen Huiju Camera Technology Co., Ltd.		
EUT	Camera	**Temperature**	24.1℃
M/N	HJX35_V21_H-V2.0	**Humidity**	54%
Test Mode	Working	**Criterion**	A
Test Engineer	Peng Dong	**Test Voltage**	DC 5V

Test Level (A/M)	Testing Duration	Coil Orientation	Criterion	Result
1	5 mins	X	A	PASS
1	5 mins	Y	A	PASS
1	5 mins	Z	A	PASS

Note:

8. PHOTOGRAPHS OF TEST SETUP



Test Setup Photo of Radiated Measurement (30MHz~1GHz)

Test Setup Photo of Electrostatic Discharge Test

Test Setup Photo of Magnetic Field Immunity Test

9. PHOTOGRAPHS OF THE EUT

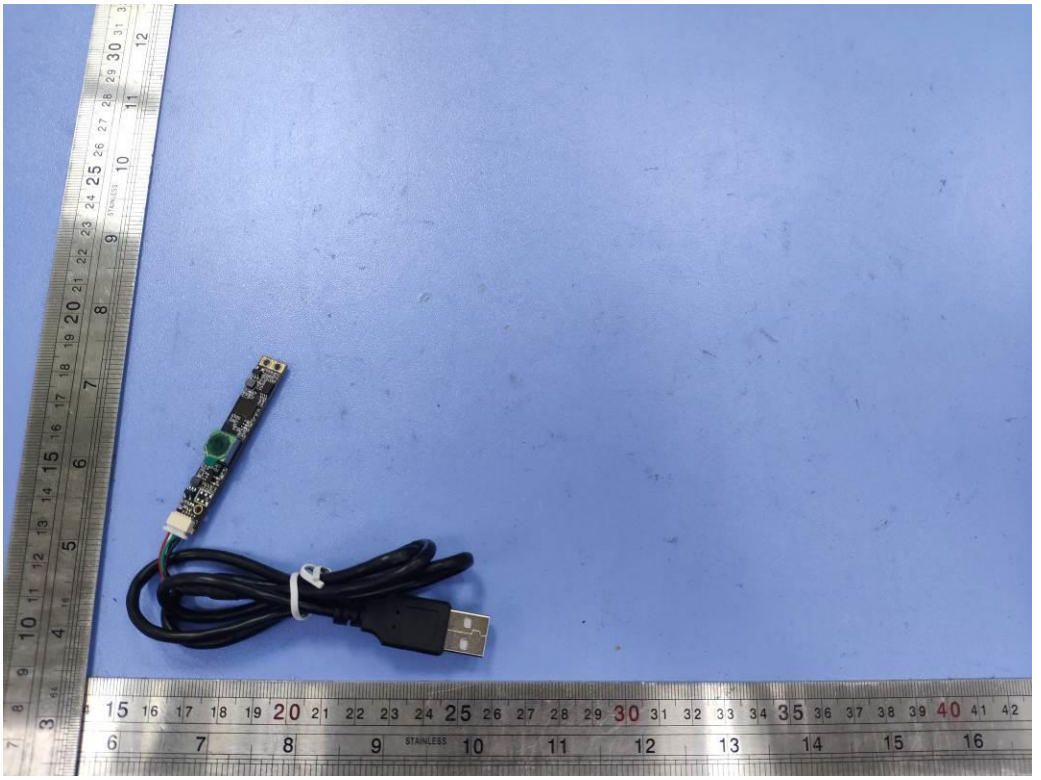


Fig. 1

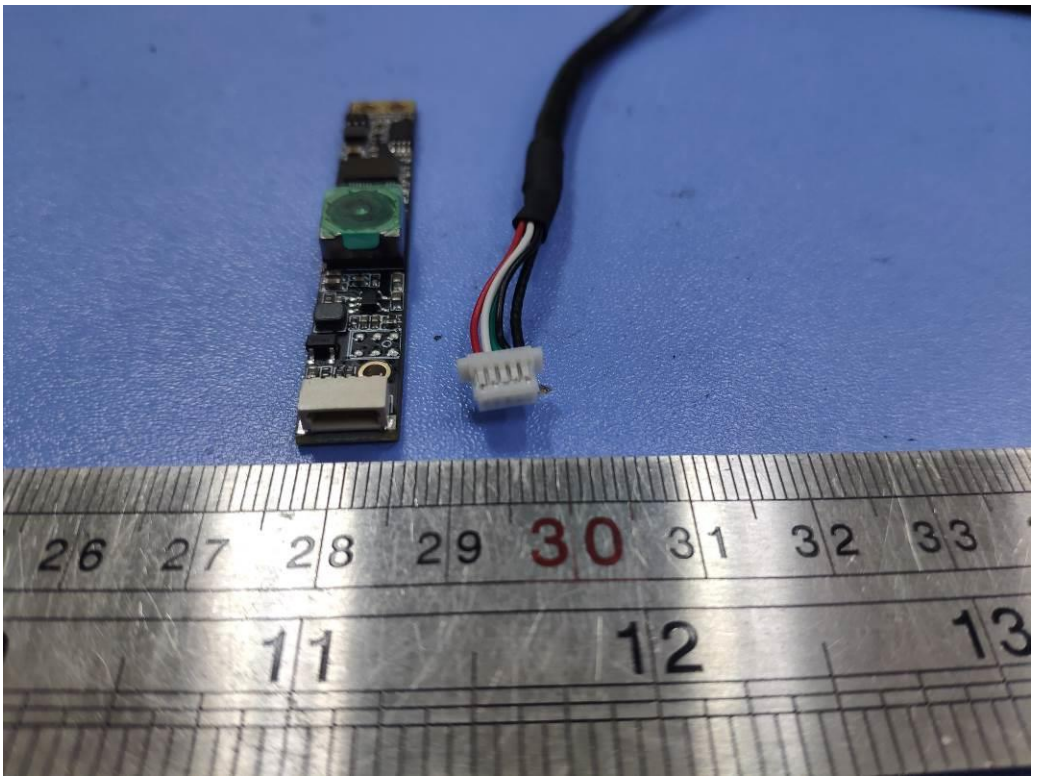


Fig. 2

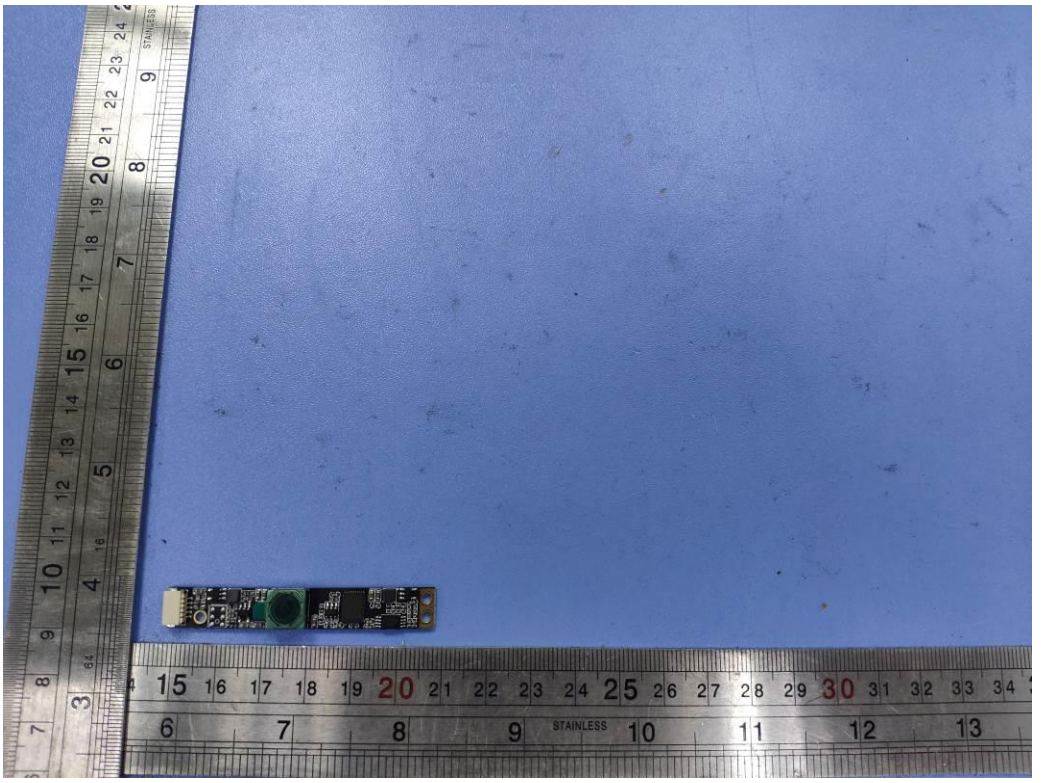


Fig. 3

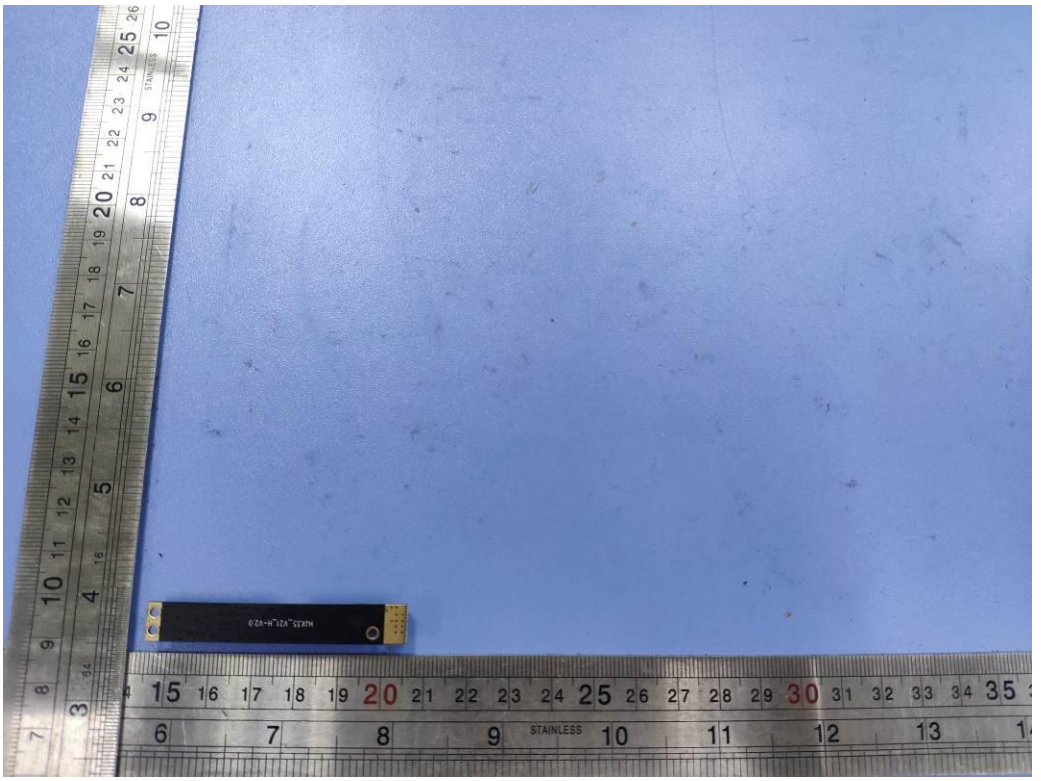


Fig. 4

----------THE END OF TEST REPORT----------